

# W153F

Spread Spectrum FTG for SiS530 and 620 Chip Sets

#### Features

- Maximized EMI suppression using Cypress's Spread Spectrum technology
- Single-chip system frequency synthesizer for SiS530 and SiS620 core logic chip sets
- Three copies of CPU output
- Six copies of PCI output
- One 48-MHz output for USB
- One 24/48 MHz selectable output for SIO
- Three buffered reference outputs
- One IOAPIC output
- Thirteen SDRAM outputs provide support for 3 DIMMs
- SMBus interface for programming allows jumperless frequency selection

### **Key Specifications**

Block Diagram

CPU Cycle-to-Cycle Jitter:	250 ps
CPU to CPU Output Skew:	175 ps
PCI to PCI Output Skew:	250 ps
CPU to PCI Output Skew (Synch. mode):	1–4 ns
V <sub>DDQ3</sub>	3.3V ± 5%
$V_{DDQ2}$	2.5V ± 5%

#### Table 1. Pin Selectable Frequency

SD_S EL	FS2	FS1	FS0	CPU1:3 (MHz)	SDRAM (MHz)	PCI	
0	0	0	0	90	90	CPU/3	
0	0	0	1	83.3	55.53	CPU/2.5	
0	0	1	0	95.25	63.5	CPU/3	
0	0	1	1	66.8	100	CPU/2	
0	1	0	0	105	105	CPU/3	
0	1	0	1	112	112 74.67		
0	1	1	0	Reserved			
0	1	1	1		Reserved		
1	0	0	0	66.8	66.8	CPU/2	
1	0	0	1	75	75	CPU/2.5	
1	0	1	0	83.3	83.3	CPU/2.5	
1	0	1	1	95.25	95.25	CPU/3	
1	1	0	0	100.2	100.2	CPU/3	
1	1	0	1	112	112	CPU/3	
1	1	1	0	Reserved			
1	1	1	1	Reserved			









## **Pin Definitions**

Pin Name	Pin No.	Pin Type	Pin Description
CPU1:3	43, 41, 40	0	<b>CPU Clock Outputs:</b> See <i>Table 1</i> and <i>Table 5</i> for detailed frequency information. Output voltage swing is controlled by voltage applied to VDDQ2.
PCI0/FS1	7	I/O	<b>PCI Clock Outputs 0/Frequency Selection 1:</b> PCI clock outputs. Output voltage swing is controlled by voltage applied to VDDQ3. Shortly after initial power-up the pin is sampled as an input to determine CPU, SDRAM, and PCI operating frequencies.
PCI1/FS2	8	I/O	<b>PCI Clock Outputs 1/Frequency Selection 2:</b> PCI clock outputs. Output voltage swing is controlled by voltage applied to VDDQ3. Shortly after initial power-up the pin is sampled as an input to determine CPU, SDRAM, and PCI operating frequencies.
PCI2:5	10, 11, 12, 13	0	<b>PCI Clock Outputs 2 through 5:</b> PCI clock outputs. Output voltage swing is controlled by voltage applied to VDDQ3.
IOAPIC	47	0	<b>IOAPIC Clock Output:</b> Provides 14.318 MHz fixed frequency. The output voltage swing is controlled by VDDQ2.
48MHz/FS0	26	I/O	<b>48-MHz Output/Frequency Select 0:</b> 48 MHz is provided in normal operation. In standard systems, this output can be used as the reference for the Universal Serial Bus. Upon power-up FS0 input will be latched, which will set clock frequencies as described in <i>Table 1</i> . This output does not have Spread Spectrum modulation.
SIO/ SEL24_48#MHz	25	I/O	Super I/O Output / Super I/O Frequency Select: This output is used for the clock input for a Super I/O chip. Upon power-up its input will be latched. If the input is a logic 1 state, SIO will be set to 24 MHz. Otherwise, the output will be set to 48 MHz.
REF1/ SD_SEL	46	I/O	<i>I/O Dual Function REF1/ Synchronous DRAM Interface Mode Selection:</i> Upon power-up, the input will be latched, which will set clock frequencies as described in <i>Table 1</i> . When used as an output, this pin provides a fixed frequency signal determined by the reference signal provided at X1/X2 pins.
REF2/ CPU3.3#_2.5	44	I/O	<i>I/O Dual Function REF2/CPU Voltage Select:</i> Upon power-up, the input will be latched. If the input is a logic 1 state, CPU1:3 will be configured for 2.5V operations, otherwise they are configured for 3.3V. When used as an output, this pin provides a fixed frequency signal determined by the reference signal provided at X1/X2 pins.
REF0	2	I/O	<i>Fixed 14.318-MHz Output 0:</i> This pin provides a fixed clock signal equal in frequency to the reference signal provided at the X1/X2 pins.
SDRAM0:12	38, 37, 35, 34, 32, 31, 29, 28, 21, 20, 18, 17, 15	0	<b>Buffered Outputs:</b> These thirteen dedicated outputs provide copies of the signal provided at the SDRAMIN input. The swing is set by VDDQ3.
SCLK	24	I	Clock pin for SMBus circuitry.
SDATA	23	I/O	Data pin for SMBus circuitry.
X1	4	I	<i>Crystal Connection or External Reference Frequency Input:</i> This pin has dual functions. It can be used as an external 14.318-MHz crystal connection or as an external reference frequency input.
X2	5	I	<i>Crystal Connection:</i> An input connection for an external 14.318-MHz crystal. If using an external reference, this pin must be left unconnected.
VDDQ3	1, 6, 14, 19, 30, 36	Р	<b>Power Connection:</b> Power supply for core logic, PLL circuitry, SDRAM outputs, PCI outputs, reference outputs, 48-MHz output, and 24-MHz output. Connect to 3.3V supply.
VDDQ2	42, 48	Р	<i>Power Connection:</i> Power supply for IOAPIC and CPU0:1 output buffers. Connect to 2.5V, or 3.3V.
GND	3, 9, 16, 22, 27, 33, 39, 45	G	<i>Ground Connections:</i> Connect all ground pins to the common system ground plane.



### Overview

The W153F is a spread spectrum system timing generator designed to support SiS530 and 620 core logic chip sets. It is a highly integrated device, providing clock outputs for CPU, core logic, super I/O, PCI, and up to three SDRAM DIMMs.

## **Functional Description**

#### I/O Pin Operation

Pins 7, 8, 25, 26, 44, and 46 are dual-purpose I/O pins.

Upon power-up, each I/O pin acts as a logic input, allowing the determination of assigned device functions. A short time after power-up, the logic state of each pin is latched and each pin then becomes a clock output. This feature reduces device pin count by combining clock outputs with input select pins.

An external 10-k $\Omega$  "strapping" resistor is connected between each I/O pin and ground or V<sub>DDQ3</sub>. Connection to ground sets a "0" bit, connection to V<sub>DDQ3</sub> sets a "1" bit. *Figure 1* and *Figure 2* show two suggested methods for strapping resistor connection.

Upon W153F power-up, the first 2 ms of operation is used for input logic selection. During this period, each clock output buffer is three-stated, allowing the output strapping resistor on

each I/O pin to pull the pin and its associated capacitive clock load to either a logic high or low state. At the end of the 2-ms period, the established logic 0 or 1 condition of each I/O pin is then latched. Next the output buffer is enabled converting all I/O pins into operating clock outputs. The 2 ms timer starts when V<sub>DDQ3</sub> reaches 2.0V. The input bits can only be reset by turning V<sub>DDQ3</sub> off and then back on again.

It should be noted that the strapping resistors have no significant effect on clock output signal integrity. The drive impedance of the clock outputs is <40 $\Omega$  (nominal) which is minimally affected by the 10-kohm strap to ground or V<sub>DDQ3</sub>. As with the series termination resistor, the output strapping resistor should be placed as close to the I/O pin as possible in order to keep the interconnecting trace short. The trace from the resistor to ground or V<sub>DDQ3</sub> should be kept less than two inches in length to prevent system noise coupling during input logic sampling.

When each clock output is enabled following the 2-ms input period, target (normal) output frequency is delivered assuming that  $V_{DDQ3}$  has stabilized. If  $V_{DDQ3}$  has not yet reached full value, output frequency initially may be below target but will increase to target once  $V_{DDQ3}$  voltage has stabilized. In either case, a short output clock cycle may be produced from the CPU clock outputs when the outputs are enabled.



Figure 1. Selection Through Resistor Load Option.



Figure 2. Input Selection Through Jumper Option.



#### **CPU/PCI Frequency Selection**

CPU frequency is selected with I/O pins 46, 26, 7, and 8 (REF1/SD\_SEL, 48MHz/FS0, PCI0/FS1, and PCI1/FS2, respectively). Refer to *Table 1* for CPU/PCI frequency programming information. Alternatively, frequency selections are available through the serial data interface. Refer to *Table 3*.

### **Output Buffer Configuration**

#### **Clock Outputs**

All clock outputs are designed to drive serial terminated clock lines. The device outputs are CMOS-type, which provide rail-to-rail output swing. To accommodate the limited voltage swing required by some processors, the output buffers of CPU0:3 use a special  $V_{DDQ2}$  power supply pin that can be tied to 2.5V nominal.

#### **Crystal Oscillator**

The device requires one input reference clock to synthesize all output frequencies. The reference clock can be either an externally generated clock signal or the clock generated by the internal crystal oscillator. When using an external clock signal, pin X1 is used as the clock input and pin X2 is left open. The input threshold voltage of pin X1 is  $(V_{DDQ3})/2$ .

The internal crystal oscillator is used in conjunction with a quartz crystal connected to device pins X1 and X2. This forms a parallel-resonant crystal oscillator circuit. The device incorporates the necessary feedback resistor and crystal load capacitors. Including typical stray circuit capacitance, the total load presented to the crystal is approximately 18 pF. For optimum frequency accuracy without the addition of external capacitors, a parallel-resonant mode crystal specifying a load of 18 pF should be used. This will typically yield reference frequency accuracies within  $\pm 100$  ppm. To achieve similar accuracies with a crystal calling for a greater load, external capacitors must be added such that the total load (internal, external, and parasitic capacitors) equals that called for by the crystal.

#### **Dual Supply Voltage Operation**

The device is designed for dual power supply operation. Supply pin VDDQ3 is connected to a 3.3V supply and supply power to the internal core circuit and to the clock output buffers, except for outputs CPU0:3 and IOAPIC. Supply pins VDDQ2 may be connected to either a 2.5V or 3.3V supply, although device specifications may not be provided for both configurations.

### **Spread Spectrum Clocking**

The device generates a clock that is frequency modulated in order to increase the bandwidth that it occupies. By increasing the bandwidth of the fundamental and its harmonics, the amplitudes of the radiated electromagnetic emissions are reduced. This effect is depicted in *Figure 3*.

As shown in *Figure 3*, a harmonic of a modulated clock has a much lower amplitude than that of an unmodulated signal. The reduction in amplitude is dependent on the harmonic number and the frequency deviation or spread. The equation for the reduction is

 $dB = 6.5 + 9*log_{10}(P) + 9*log_{10}(F)$ 

Where P is the percentage of deviation and F is the frequency in MHz where the reduction is measured.

The output clock is modulated with a waveform depicted in *Figure 4.* This waveform, as discussed in "Spread Spectrum Clock Generation for the Reduction of Radiated Emissions" by Bush, Fessler, and Hardin, produces the maximum reduction in the amplitude of radiated electromagnetic emissions. The deviation selected for this chip is specified in *Table 6. Figure 4* details the Cypress spreading pattern. Cypress does offer options with more spread and greater EMI reduction. Contact your local Sales representative for details on these devices.

Spread Spectrum clocking is activated or deactivated by selecting the appropriate values for bits 1–0 in data byte 0 of the SMBus data stream. Refer to *Table 4* for more details.





Figure 3. Clock Harmonic with an without SSCG Modulation Frequency Domain Representation.



Figure 4. Typical Modulation Profile.

#### **Serial Data Interface**

The device features a two-pin, serial data interface that can be used to configure internal register settings that control particular device functions. Upon power-up, the W153F initializes with default register settings, therefore the use of this serial data interface is optional. The serial interface is write-only (to the clock chip) and is the dedicated function of device pins SDATA and SCLOCK. In motherboard applications, SDATA and SCLOCK are typically driven by two logic outputs of the chipset. Clock device register changes are normally made upon system initialization, if any are required. The interface can also be used during system operation for power management functions. summarizes the control functions of the serial data interface.

#### Operation

Data is written to the device in ten bytes of eight bits each. Bytes are written in the order shown in *Table 3*.



Table 2.	Serial Data	Interface	Control	Functions	Summary
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Control Function	Description	Common Application
Clock Output Disable	Any individual clock output(s) can be disabled. Disabled outputs are actively held LOW.	Unused outputs are disabled to reduce EMI and system power. Examples are clock out- puts to unused SDRAM DIMM socket or PCI slot.
CPU Clock Frequency Selection	Provides CPU/PCI frequency selections beyond the options that are provided by the frequency selection pin power-on default selection. Frequency is changed in a smooth and controlled fashion.	For alternate CPU devices, and power man- agement options. Smooth frequency transi- tion allows CPU frequency change under nor- mal system operation.
Output Three-state	Puts all clock outputs into a high impedance state.	Production PCB testing.
Test Mode	All clock outputs toggle in relation with X1 input, internal PLL is bypassed. Refer to <i>Table 4</i> .	Production PCB testing.
(Reserved)	Reserved function for future device revision or pro- duction device testing.	No user application. Register bit must be written as 0.

### Table 3. Byte Writing Sequence

Byte Sequence	Byte Name	Bit Sequence	Byte Description
1	Slave Address	11010010	Commands the device to accept the bits in Data Bytes 0–6 for internal register configuration. Since other devices may exist on the same common serial data bus, it is necessary to have a specific slave address for each potential receiver. The slave receiver address for the device is 11010010. Register setting will not be made if the Slave Address is not correct (or is for an alternate slave receiver).
2	Command Code	Don't Care	Unused by the device, therefore bit values are ignored (Don't Care). This byte must be included in the data write sequence to maintain proper byte allocation. The Command Code Byte is part of the standard serial communication protocol and may be used when writing to another addressed slave receiver on the serial data bus.
3	Byte Count	Don't Care	Unused by the device, therefore bit values are ignored (Don't Care). This byte must be included in the data write sequence to maintain proper byte allocation. The Byte Count Byte is part of the standard serial communication protocol and may be used when writing to another addressed slave receiver on the serial data bus.
4	Data Byte 0	Refer to	The data bits in these bytes set internal W153F registers that control
5	Data Byte 1	Table 4	Byte bit sequence is 11010010, as noted above. For description of bit
6	Data Byte 2		control functions, refer to Table 4.
7	Data Byte 3		
8	Data Byte 4		
9	Data Byte 5		
10	Data Byte 6		



### Writing Data Bytes

Each bit in the data bytes controls a particular device function except for the "reserved" bits which must be written as a logic 0. Bits are written MSB (most significant bit) first, which is bit 7.

Table 4 gives the bit formats for registers located in Data Bytes 0-6. Table 1 details additional frequency selections that are available through the serial data interface.

Table 2 details the select functions for Byte 0, bits 1 and 0.

	Affe	cted Pin		Bit C	ontrol	
Bit(s)	Pin No.	Pin Name	Control Function	0	1	Default
Data By	/te 0					
7			(Reserved)			0
6			BYTE0_SEL2	Refer to	o Table 1	0
5			BYTE0 _SEL1	Refer to	o Table 1	0
4			BYTE0_SEL0	Refer to	o Table 1	0
3			BYTE0_FS#	Frequency Controlled by FS (2:0) and SD_SEL	Frequency Controlled by BYT0_SEL (3:0)	0
2			BYTE0_SEL3	Refer to	o Table 5	0
1-0			Bit 1 Bit 0 0 0 0 1 1 0 1 1	Function (See <i>Table 6</i> Normal Operation Normal Operation Spread Spectrum On All Outputs Three-sta	5 for function details) ted	00
Data By	/te 1					
7			(Reserved)			0
6			(Reserved)			0
5			(Reserved)			0
4			(Reserved)			0
3	40	CPU3	Clock Output Disable	Low	Active	1
2	41	CPU2	Clock Output Disable	Low	Active	1
1	43	CPU1	Clock Output Disable	Low	Active	1
0			(Reserved)			0
Data By	/te 2					
7			(Reserved)			0
6	7	PCI0	Clock Output Disable	Low	Active	1
5	15	SDRAM12	Clock Output Disable	Low	Active	1
4	13	PCI5	Clock Output Disable	Low	Active	1
3	12	PCI4	Clock Output Disable	Low	Active	1
2	11	PCI3	Clock Output Disable	Low	Active	1
1	10	PCI2	Clock Output Disable	Low	Active	1
0	8	PCI1	Clock Output Disable	Low	Active	1

 Table 4. Data Bytes 0–6 Serial Configuration Map



## Table 4. Data Bytes 0-6 Serial Configuration Map (continued)

	Affected Pin			Bit Control		
Bit(s)	Pin No.	Pin Name	Control Function	0	1	Default
Data By	rte 3					
7	28	SDRAM7	Clock Output Disable	Low	Active	1
6	29	SDRAM6	Clock Output Disable	Low	Active	1
5	31	SDRAM5	Clock Output Disable	Low	Active	1
4	32	SDRAM4	Clock Output Disable	Low	Active	1
3	34	SDRAM3	Clock Output Disable	Low	Active	1
2	35	SDRAM2	Clock Output Disable	Low	Active	1
1	37	SDRAM1	Clock Output Disable	Low	Active	1
0	38	SDRAM0	Clock Output Disable	Low	Active	1
Data By	rte 4					
7			(Reserved)			0
6			(Reserved)			0
5			(Reserved)			0
4			(Reserved)			0
3	17	SDRAM11	Clock Output Disable	Low	Active	1
2	18	SDRAM10	Clock Output Disable	Low	Active	1
1	20	SDRAM9	Clock Output Disable	Low	Active	1
0	21	SDRAM8	Clock Output Disable	Low	Active	1
Data By	rte 5					
7			(Reserved)			0
5			(Reserved)			0
5			(Reserved)			0
4	47	IOAPIC	Clock Output Disable	Low	Active	1
3			(Reserved)			0
2	44	REF2	Clock Output Disable	Low	Active	1
1	46	REF1	Clock Output Disable	Low	Active	1
0	2	REF0	Clock Output Disable	Low	Active	1
Data By	rte 6					
7			(Reserved)			0
6			(Reserved)			0
5			(Reserved)			0
4			(Reserved)			0
3			(Reserved)			0
2			(Reserved)			0
1			(Reserved)			0
0			(Reserved)			0



Input Conditions				Output Frequency			
Bit 2 BYTE0_SEL3	Bit 6 BYTE0_SEL2	Bit 5 BYTE0_SEL1	Bit 4 BYTE0_SEL0	CPU (MHz)	SDRAM (MHz)	PCI Clocks (MHz)	
0	0	0	0	90	90	CPU/3	
0	0	0	1	83.3	55.53	CPU/2.5	
0	0	1	0	95.25	63.5	CPU/3	
0	0	1	1	66.8	100	CPU/2	
0	1	0	0	105	105	CPU/3	
0	1	0	1	112	74.67	CPU/3	
0	1	1	0	Reserved			
0	1	1	1		Reserved		
1	0	0	0	66.8	66.8	CPU/2	
1	0	0	1	75	75	CPU/2.5	
1	0	1	0	83.3	83.3	CPU/2.5	
1	0	1	1	95.25	95.25	CPU/3	
1	1	0	0	100.2	100.2	CPU/3	
1	1	0	1	112	112	CPU/3	
1	1	1	0	Reserved			
1	1	1	1	Reserved			

#### Table 5. Additional Frequency Selections through Serial Data Interface Data Bytes

#### Table 6. Select Function for Data Byte 0, Bits 0:1

	Input Conditions Data Byte 0		Output Conditions				
			CPUI0-2		DEE0.1		
Function	Bit 1	Bit 0	SDRAM0:11	PCI_F, PCI0:5	IOAPIC	48/24MHZ	
Normal Operation	0	0	Note 2	Note 2	14.318 MHz	48/24 MHz	
Normal Operation	0	1	Note 2	Note 2	14.318 MHz	48/24 MHz	
Spread Spectrum On	1	0	Note 2 ±0.5% spread	Note 2 ±0.5% spread	14.318 MHz	48/24 MHz	
Three-state	1	1	Hi-Z	Hi-Z	Hi-Z	Hi-Z	

Notes:

CPU, SDRAM and PCI frequency selections are listed in *Table 4*.
 In Test Mode, the 48/24MHz clock outputs are:

 X1/2 for 48-MHz output
 X1/4 for 24-MHz output



## **Absolute Maximum Ratings**

Stresses greater than those listed in this table may cause permanent damage to the device. These represent a stress rating only. Operation of the device at these or any other conditions above those specified in the operating sections of this specification is not implied. Maximum conditions for extended periods may affect reliability.

Parameter	Description	Rating	Unit
V <sub>DD</sub> , V <sub>IN</sub>	Voltage on Any Pin with Respect to GND	-0.5 to +7.0	V
T <sub>STG</sub>	Storage Temperature	-65 to +150	°C
Τ <sub>B</sub>	Ambient Temperature under Bias	-55 to +125	°C
T <sub>A</sub>	Operating Temperature	0 to +70	°C
ESD <sub>PROT</sub>	Input ESD Protection	2 (min)	kV

### 3.3V DC Electrical Characteristics: (CPU3.3#\_2.5 Input = 0)

 $T_A = 0^{\circ}C$  to +70°C,  $V_{DDQ3} = V_{DDQ2} = 3.3V\pm5\%$  (3.135–3.465V)

Parameter	Descripti	on	Test Condition	Min.	Тур.	Max.	Unit
Supply Cur	rent						
I <sub>DD</sub>	Combined 3.3V Supply	Current	CPU0:3 = 66.8 MHz Outputs Loaded <sup>[4]</sup>			365	mA
Logic Input	S		I				J
V <sub>IL</sub>	Input Low Voltage					0.8	V
V <sub>IH</sub>	Input High Voltage			2.0			V
IIL	Input Low Current <sup>[5]</sup>					10	μA
I <sub>IH</sub>	Input High Current <sup>[5]</sup>					10	μA
Clock Outp	uts						
V <sub>OL</sub>	Output Low Voltage		I <sub>OL</sub> = 1 mA			50	mV
V <sub>OH</sub>	Output High Voltage		$I_{OH} = -1 \text{ mA}$	3.1			V
I <sub>OL</sub>	Output Low Current:	CPU1:3	V <sub>OL</sub> = 1.5V	55	75	105	mA
		SDRAM0:11		80	110	155	
		PCI_F, PCI0:5		55	75	105	
		IOAPIC		100	135	190	
		REF0		60	75	90	
		REF1		45	60	75	
		48/24MHZ		55	75	105	
I <sub>OH</sub>	Output High Current:	CPU1:3	V <sub>OH</sub> = 1.5V	55	85	125	mA
		SDRAM0:11		80	120	175	
		PCI_F, PCI0:5		55	85	125	
		IOAPIC		100	150	220	
		REF0		60	85	110	]
		REF1		45	65	90	
		48/24MHZ		55	85	125	

Notes:

4. 5.

All clock outputs loaded with 6"  $60\Omega$  traces with 22 pF capacitors. W153F logic inputs have internal pull-up devices (pull-ups not full CMOS level).



## 3.3V DC Electrical Characteristics: (CPU3.3#\_2.5 Input = 0) (continued)

 $T_A = 0^{\circ}C$  to +70°C,  $V_{DDQ3} = V_{DDQ2} = 3.3V\pm5\%$  (3.135–3.465V)

Parameter	Description	Test Condition	Min.	Тур.	Max.	Unit
Crystal Osc	illator	·				
V <sub>TH</sub>	X1 Input threshold Voltage <sup>[6]</sup>			1.65		V
C <sub>LOAD</sub>	Load Capacitance, Imposed on External Crystal <sup>[7]</sup>			18		pF
C <sub>IN,X1</sub>	X1 Input Capacitance <sup>[8]</sup>	Pin X2 unconnected		28		pF
Pin Capacit	ance/Inductance					
C <sub>IN</sub>	Input Pin Capacitance	Except X1 and X2			5	рF
C <sub>OUT</sub>	Output Pin Capacitance				6	pF
L <sub>IN</sub>	Input Pin Inductance				7	nH
Serial Input	Port					
V <sub>IL</sub>	Input Low Voltage				0.3V <sub>DD</sub>	V
V <sub>IH</sub>	Input High Voltage		$0.7V_{DD}$			V
IIL	Input Low Current	No internal pull-up/down on SCLOCK			10	μA
IIH	Input High Current	No internal pull-up/down on SCLOCK			10	μA
I <sub>OL</sub>	Sink Current into SDATA Open Drain N-Channel Device On	$I_{OL} = 0.3 V_{DD}$	6			mA
C <sub>IN</sub>	Input Capacitance of SDATA and SCLOCK				10	pF
C <sub>SDATA</sub>	Total Capacitance of SDATA Bus				400	pF
C <sub>SCLOCK</sub>	Total Capacitance of SCLOCK Bus				400	pF

Notes:

X1 input threshold voltage (typical) is (V<sub>DDQ3</sub>)/2.
 The W153F contains an internal crystal load capacitor between pin X1 and ground and another between pin X2 and ground. Total load placed on crystal is 18 pF; this includes typical stray capacitance of short PCB traces to crystal.
 X1 input capacitance is applicable when driving X1 with an external clock source (X2 is left unconnected).



## **2.5V DC Electrical Characteristics** (CPU3.3#\_2.5 Input = 1)

 $T_A = 0^{\circ}C$  to +70°C,  $V_{DDQ3} = 3.3V\pm5\%$  (3.135–3.456V),  $V_{DDQ2} = 2.5V\pm5\%$  (2.375–2.625V)

7.	DEGO		DDQL				
Parameter	Descript	ion	Test Condition	Min.	Тур.	Max.	Unit
Supply Cur	rent						
I <sub>DD-3.3V</sub>	Combined 3.3V Supply	v Current	CPU0:3 = 66.8MHz Outputs Loaded <sup>[4]</sup>			300	mA
I <sub>DD-2.5</sub>	Combined 2.5V Supply	Current	CPU0:3= 66.8MHz Outputs Loaded <sup>[4]</sup>			50	mA
Logic Input	ts						
V <sub>IL</sub>	Input Low Voltage					0.8	V
V <sub>IH</sub>	Input High Voltage	t High Voltage		2.0			V
IIL	Input Low Current <sup>[5]</sup>	ut Low Current <sup>[5]</sup>				10	μA
I <sub>IH</sub>	Input High Current <sup>[5]</sup>	ut High Current <sup>[5]</sup>				10	μA
Clock Outp	outs						<u>.</u>
V <sub>OL</sub>	Output Low Voltage		I <sub>OL</sub> = 1 mA			50	mV
V <sub>OH</sub>	Output High Voltage		I <sub>OH</sub> = -1 mA	2.2			V
I <sub>OL</sub>	Output Low Current:	CPU1:3	V <sub>OL</sub> = 1.25V	45	70	105	mA
		SDRAM0:11	V <sub>OL</sub> = 1.5V	80	110	155	
		PCI_F, PCI0:5	V <sub>OL</sub> = 1.5V	55	75	105	
		IOAPIC	V <sub>OL</sub> = 1.25V	55	85	130	
		REF0	V <sub>OL</sub> = 1.5V	60	75	90	
		REF1	V <sub>OL</sub> = 1.5V	45	60	75	
		48/24MHZ	V <sub>OL</sub> = 1.5V	55	75	105	]
I <sub>OH</sub>	Output High Current:	CPU1:3	V <sub>OH</sub> = 1.25V	40	65	95	mA
		SDRAM0:11	V <sub>OH</sub> = 1.5V	80	120	175	]
		PCI_F, PCI0:5	V <sub>OH</sub> = 1.5V	55	85	125	
		IOAPIC	V <sub>OH</sub> = 1.25V	50	80	120	
		REF0	V <sub>OH</sub> = 1.5V	60	85	110	]
		REF1	V <sub>OH</sub> = 1.5V	45	65	90	]
		48/24MHZ	V <sub>OH</sub> = 1.5V	55	85	125	]



## 3.3V AC Electrical Characteristics (CPU3.3#\_2.5 Input = 0)

 $T_A$  = 0°C to +70°C,  $V_{DDQ3}$  =  $V_{DDQ2}$  = 3.3V±5% (3.135–3.465V),  $f_{XTL}$  = 14.31818 MHz Spread Spectrum function turned off

AC clock parameters are tested and guaranteed over stated operating conditions using the stated lump capacitive load at the clock output.

			CPU = 66.8 MHz		MHz	CPL	J = 100	MHz	
Parameter	Description	Test Condition/Comments	Min.	Тур.	Max.	Min.	Тур.	Max.	Unit
t <sub>P</sub>	Period	Measured on rising edge at 1.5V	15				10	10.5	ns
f	Frequency, Actual	Determined by PLL divider ratio		66.8			100.2		MHz
t <sub>H</sub>	High Time	Duration of clock cycle above 2.4V	5.2			3.0			ns
tL	Low Time	Duration of clock cycle below 0.4V	5			2.8			ns
t <sub>R</sub>	Output Rise Edge Rate	Measured from 0.4V to 2.4V	1		4	1		4	V/ns
t <sub>F</sub>	Output Fall Edge Rate	Measured from 2.4V to 0.4V	1		4	1		4	V/ns
t <sub>D</sub>	Duty Cycle	Measured on rising and falling edge at 1.5V	45		55			55	%
t <sub>JC</sub>	Jitter, Cycle-to-Cycle	Measured on rising edge at 1.5V. Max- imum difference of cycle time between two adjacent cycles.			250			250	ps
t <sub>SK</sub>	Output Skew	Measured on rising edge at 1.5V			175			175	ps
f <sub>ST</sub>	Frequency Stabilization from Power-up (cold start)	Assumes full supply voltage reached within 1 ms from power-up. Short cy- cles exist prior to frequency stabiliza- tion.			3			3	ms
Z <sub>o</sub>	AC Output Impedance	Average value during switching transi- tion. Used for determining series termi- nation value.	15	20	30		13.5		Ω

## CPU Clock Outputs, (Lump Capacitance Test Load = 20 pF

## SDRAM Clock Outputs, (Lump Capacitance Test Load = 30 pF)

		SDF	RAM = 66.8	3 MHz	SDF	MHz		
Parameter	Description	Min.	Тур.	Max.	Min.	Тур.	Max.	Unit
t <sub>P</sub>	Period	15				10		ns
f	Frequency, Actual		66.8			100.2		MHz
t <sub>R</sub>	Output Rise Edge Rate	1		4	1		4	V/ns
t <sub>F</sub>	Output Fall Edge Rate	1		4	1		4	V/ns
t <sub>D</sub>	Duty Cycle	45		55	45		55	%
t <sub>JC</sub>	Jitter, Cycle-to-Cycle			250			250	ps
t <sub>SK</sub>	Output Skew		100			100		ps
t <sub>SK</sub>	CPU to SDRAM Clock Skew			500			500	ps
f <sub>ST</sub>	Frequency Stabilization from Power-up (cold start)			3			3	ms
Zo	AC Output Impedance	10	15	20	10	15	20	Ω



		Test	PCI = 33.4 MHz			
Parameter	Description	Condition/Comments	Min.	Тур.	Max.	Unit
t <sub>P</sub>	Period	Measured on rising edge at 1.5V	30			ns
f	Frequency, Actual	Determined by PLL divider ratio		33.4		MHz
t <sub>H</sub>	High Time	Duration of clock cycle above 2.4V	12			ns
tL	Low Time	Duration of clock cycle below 0.4V	12			ns
t <sub>R</sub>	Output Rise Edge Rate	Measured from 0.4V to 2.4V	1		4	V/ns
t <sub>F</sub>	Output Fall Edge Rate	Measured from 2.4V to 0.4V	1		4	V/ns
t <sub>D</sub>	Duty Cycle	Measured on rising and falling edge at 1.5V	45		55	%
t <sub>JC</sub>	Jitter, Cycle-to-Cycle	Measured on rising edge at 1.5V. Maximum difference of cycle time between two adjacent cycles.			250	ps
t <sub>SK</sub>	Output Skew	Measured on rising edge at 1.5V			250	ps
t <sub>O</sub>	CPU to PCI Clock Skew	Covers all CPU/SDRAM outputs. Measured on rising edge at 1.5V	1		4	ns
f <sub>ST</sub>	Frequency Stabilization from Power-up (cold start)	Assumes full supply voltage reached within 1 ms from power-up. Short cycles exist prior to frequency stabilization			3	ms
Z <sub>o</sub>	AC Output Impedance	Average value during switching transition. Used for determining series termination value.	15	20	30	ohm

# PCI Clock Outputs, PCI\_F and PCI0:5 (Lump Capacitance Test Load = 30 pF)

## IOAPIC Clock Output (Lump Capacitance Test Load = 20 pF)

Parameter	Description	Test Condition/Comments	Min.	Тур.	Max.	Unit
f	Frequency, Actual	Frequency generated by crystal oscillator		14.31818		MHz
t <sub>R</sub>	Output Rise Edge Rate	Measured from 0.4V to 2.4V	1		4	V/ns
t <sub>F</sub>	Output Fall Edge Rate	Measured from 2.4V to 0.4V	1		4	V/ns
t <sub>D</sub>	Duty Cycle	Measured on rising and falling edge at 1.5V	45		55	%
f <sub>ST</sub>	Frequency Stabilization from Power-up (cold start)	Assumes full supply voltage reached within 1 ms from power-up. Short cycles exist prior to frequency stabilization.			1.5	ms
Zo	AC Output Impedance	Average value during switching transition. Used for determining series termination value.	8	12	15	ohm

# REF0 Clock Output (Lump Capacitance Test Load = 45 pF)

Parameter	Description	Test Condition/Comments	Min.	Тур.	Max.	Unit
f	Frequency, Actual	Frequency generated by crystal oscillator	1	14.31818		MHz
t <sub>R</sub>	Output Rise Edge Rate	Measured from 0.4V to 2.4V	1		4	V/ns
t <sub>F</sub>	Output Fall Edge Rate	Measured from 2.4V to 0.4V	1		4	V/ns
t <sub>D</sub>	Duty Cycle	Measured on rising and falling edge at 1.5V	45		55	%
f <sub>ST</sub>	Frequency Stabilization from Power-up (cold start)	Assumes full supply voltage reached within 1 ms from power-up. Short cycles exist prior to frequency stabilization.			1.5	ms
Zo	AC Output Impedance	Average value during switching transition. Used for determining series termination value.	17	20	25	ohm



Parameter	Description	Test Condition/Comments	Min.	Тур.	Max.	Unit
f	Frequency, Actual	Frequency generated by crystal oscillator		14.31818	3	MHz
t <sub>R</sub>	Output Rise Edge Rate	Measured from 0.4V to 2.4V	1		4	V/ns
t <sub>F</sub>	Output Fall Edge Rate	Measured from 2.4V to 0.4V	1		4	V/ns
t <sub>D</sub>	Duty Cycle	Measured on rising and falling edge at 1.5V	45		55	%
f <sub>ST</sub>	Frequency Stabilization from Power-up (cold start)	Assumes full supply voltage reached within 1 ms from power-up. Short cycles exist prior to frequency stabilization.			1.5	ms
Zo	AC Output Impedance	Average value during switching transition. Used for determining series termination value.	20	25	35	ohm

# REF1 Clock Output (Lump Capacitance Test Load = 20 pF)

## 48/24MHZ Clock Outputs (Lump Capacitance Test Load = 20 pF)

Parameter	Description	Test Condition/Comments	Min.	Тур.	Max.	Unit
f	Frequency, Actual	Determined by PLL divider ratio (see m/n below)	48	.008/24.0	004	MHz
f <sub>D</sub>	Deviation from 48 MHz	(48.008 - 48)/48		+167		ppm
m/n	PLL Ratio	(14.31818 MHz x 57/17 = 48.008 MHz)	57/17, 57/34			
t <sub>R</sub>	Output Rise Edge Rate	Measured from 0.4V to 2.4V	1		4	V/ns
t <sub>F</sub>	Output Fall Edge Rate	Measured from 2.4V to 0.4V	1		4	V/ns
t <sub>D</sub>	Duty Cycle	Measured on rising and falling edge at 1.5V	45		55	%
f <sub>ST</sub>	Frequency Stabilization from Power-up (cold start)	Assumes full supply voltage reached within 1 ms from power-up. Short cycles exist prior to frequency stabilization.			3	ms
Z <sub>o</sub>	AC Output Impedance	Average value during switching transition. Used for determining series termination value.	15	20	30	ohm

## **Serial Input Port**

Parameter	Description	Test Condition	Min.	Тур.	Max.	Unit
f <sub>SCLOCK</sub>	SCLOCK Frequency	Normal Mode	0		100	kHz
t <sub>STHD</sub>	Start Hold Time		4.0			μs
t <sub>LOW</sub>	SCLOCK Low Time		4.7			μs
t <sub>HIGH</sub>	SCLOCK High Time		4.0			μs
t <sub>DSU</sub>	Data Set-up Time		250			ns
t <sub>DHD</sub>	Data Hold Time	Transmitter should provide a 300-ns hold time to ensure proper timing at the receiver	0			ns
t <sub>R</sub>	Rise Time, SDATA and SCLOCK	From $0.3V_{DD}$ to $0.7V_{DD}$			1000	ns
t <sub>F</sub>	Fall Time, SDATA and SCLOCK	From $0.7V_{DD}$ to $0.3V_{DD}$			300	ns
t <sub>STSU</sub>	Stop Set-up Time		4.0			μs
t <sub>SPF</sub>	Bus Free Time between Stop and Start Condition		4.7			μs
t <sub>SP</sub>	Allowable Noise Spike Pulse Width				50	ns



## 2.5V AC Electrical Characteristics (CPU3.3#\_2.5 Input = 1)<sup>[9]</sup>

 $T_{A} = 0^{\circ}C \text{ to } +70^{\circ}C, V_{DDQ3} = 3.3V \pm 5\% \text{ (3.135} - 3.465V), V_{DDQ2} = 2.5V \pm 5\% \text{ (2.375} - 2.625V), f_{XTL} = 14.31818 \text{ MHz}$ 

### CPU Clock Outputs, (Lump Capacitance Test Load = 20 pF)

			CPU = 66.8 MHz		MHz	CPU = 100 MHz			
Parameter	Description	Test Condition/Comments	Min.	Тур.	Max.	Min.	Тур.	Max.	Unit
t <sub>P</sub>	Period	Measured on rising edge at 1.25V	15			10		10.5	ns
f	Frequency, Actual	Determined by PLL divider ratio		66.8			100.2		MHz
t <sub>H</sub>	High Time	Duration of clock cycle above 2.0V	5.2			3			ns
tL	Low Time	Duration of clock cycle below 0.4V	5			2.8		4	ns
t <sub>R</sub>	Output Rise Edge Rate	Measured from 0.4V to 2.0V	0.8		3	1		4	V/ns
t <sub>F</sub>	Output Fall Edge Rate	Measured from 2.0V to 0.4V	0.8		3	15		45	V/ns
t <sub>D</sub>	Duty Cycle	Measured on rising and falling edge at 1.25V	45		55	45		55	%
t <sub>JC</sub>	Jitter, Cycle-to-Cycle	Measured on rising edge at 1.25V. Maximum difference of cycle time be- tween two adjacent cycles.			250			250	ps
t <sub>SK</sub>	Output Skew	Measured on rising edge at 1.25V			175			175	ps
f <sub>ST</sub>	Frequency Stabilization from Power-up (cold start)	Assumes full supply voltage reached within 1 ms from power-up. Short cycles exist prior to frequency stabilization.			3			3	ms
Zo	AC Output Impedance	Average value during switching transi- tion. Used for determining series termi- nation value.	15	20	30	15	20	30	Ω

## IOAPIC Clock Output (Lump Capacitance Test Load = 20pF)

Parameter	Description	Test Condition/Comments	Min.	Тур.	Max.	Unit
f	Frequency, Actual	Frequency generated by crystal oscillator		14.31818	3	MHz
t <sub>R</sub>	Output Rise Edge Rate	Measured from 0.4V to 2.0V	1		4	V/ns
t <sub>F</sub>	Output Fall Edge Rate	Measured from 2.0V to 0.4V	1		4	V/ns
t <sub>D</sub>	Duty Cycle	Measured on rising and falling edge at 1.25V	45		55	%
f <sub>ST</sub>	Frequency Stabilization from Power-up (cold start)	Assumes full supply voltage reached within 1 ms from power-up. Short cycles exist prior to frequency stabilization.			1.5	ms
Z <sub>o</sub>	AC Output Impedance	Average value during switching transition. Used for determining series termination value.	10	15	25	ohm

## **Ordering Information**

Part Number	Package
W153F	H = SSOP (300 mils)

Note:

9. AC clock parameters are tested and guaranteed over stated operating conditions using the stated lump capacitive load at the clock output.



## **Mechanical Package Outline**



COMMON VARI-ATIONS AA AB AAAb 41 34 34 ñ 0.127 0.127 0.127 SEE b c c L L e 0.254 0.152 4 7.42 7.52 .635 BSC 10.4<sup>-</sup> 0.41 1.02 0.6 . SEE 6 10 2.54 36

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Document Title: W153F Spread Spectrum FTG for SiS530 and 620 Chip Sets Document Number: 38-07003								
REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change				
**	111610	03/06/02	IKA	New data sheet				